

Search Notes



Application/Control No.

10/757,304

Examiner

Patrick J. Assouad

Applicant(s)/Patent under Reexamination

SEKINO, TAKASHI

Art Unit

2857

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
324	763	10/12/05	PM
702	117 120	↓	↓
SEE EMT. attached.			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
PLUS report reviewed and attached.	10/12/05	PM
EAT searched. See attached.	10/12/05	PM
Broad search of:		
324/500, 527, 537		
763, 765		
702/57, 58, 64, 65 117, 120		
714/724, 735, 738		
327/1, 100		
Keywords:		
parasitic capacitance		
driver/comparator		
trans. line		
test pattern		
DC voltage test		
AC test		